



Maximum Ratings @T_A = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source voltage			V_{DSS}	30	V
Gate-Source voltage			V _{GS}	±20	V
Continuous Drain current	V _{GS} = 10V	(Notes 3 & 5)	I _D	7.2	
		T _A = 70°C (Notes 3 & 5)		5.8	۸
		(Notes 2 & 5)		5.7	А
		(Notes 2 & 6)		6.8	
Pulsed Drain current	Drain current V _{GS} = 10V (Notes 4 & 5)		I _{DM}	34	Α
Continuous Source current (Body diode) (Notes 3 & 9		(Notes 3 & 5)	I _S	3.3	Α
Pulsed Source current (Body diode) (Notes 4 & 5)		I _{SM}	34	Α	

Thermal Characteristics @T_A = 25°C unless otherwise specified

Characteristic	Symbol	Value	Unit		
	(Notes 2 & 5)		1.3 10.0		
Power dissipation Linear derating factor	(Notes 2 & 6)	P_{D}	1.8 14.3	W mW/°C	
	(Notes 3 & 5)		2.0 15.9		
	(Notes 2 & 5)		100		
Thermal Resistance, Junction to Ambient	(Notes 2 & 6)	$R_{\theta JA}$	70	°C/W	
	(Notes 3 & 5)	**	63		
Thermal Resistance, Junction to Lead	(Notes 5 & 7)	$R_{ heta JL}$	53	°C/W	
Operating and storage temperature range	T _J , T _{STG}	-55 to 150	°C		

Notes:

- 2. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is 2. For a device strate mounted of 25mm x 25mm x 1.5mm FR4 FCB with high coverage of single sided 102 copper, in still all conditions.

 3. Same as note (2), except the device is measured at t ≤ 10 sec.

 4. Same as note (2), except the device is pulsed with D= 0.02 and pulse width 300 μs. The pulse current is limited by the maximum junction temperature.

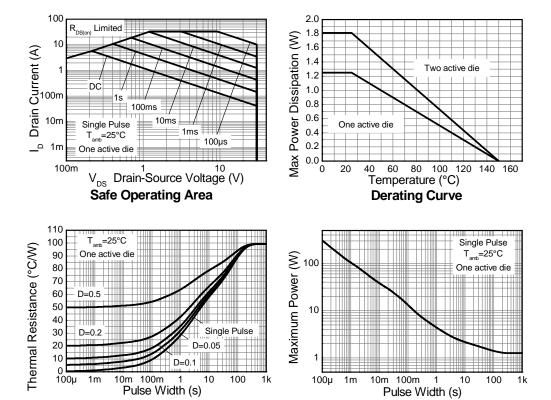
 5. For a device with one active die.

 6. For a device with two active die running at equal power.

- 7. Thermal resistance from junction to solder-point (at the end of the drain lead): the device is operating in a steady-state condition.



Thermal Characteristics



Pulse Power Dissipation

Transient Thermal Impedance





Electrical Characteristics @T_A = 25°C unless otherwise specified

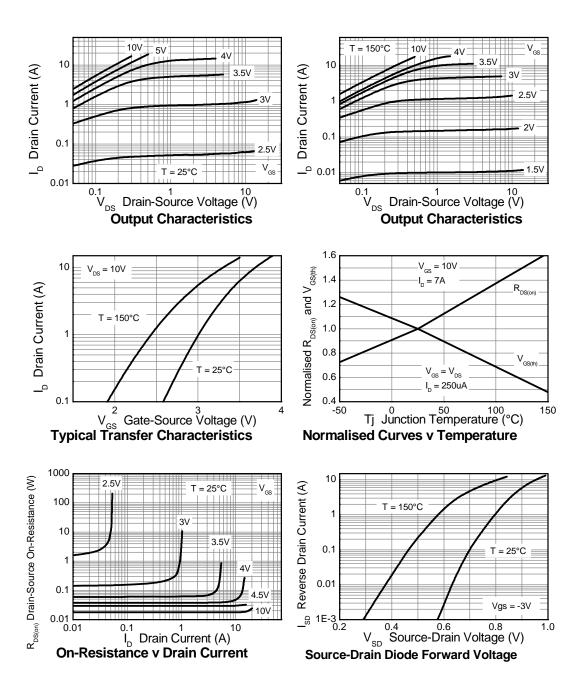
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition		
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$I_D = 250 \mu A, V_{GS} = 0 V$		
Zero Gate Voltage Drain Current	I _{DSS}	_	_	0.5	μА	V _{DS} = 30V, V _{GS} = 0V		
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	V _{GS} = ±20V, V _{DS} = 0V		
ON CHARACTERISTICS								
Gate Threshold Voltage	V _{GS(th)}	1.0		3.0	V	I _D = 250μA, V _{DS} = V _{GS}		
Static Drain-Source On-Resistance (Note 8)	0	_		0.024	Ω	V _{GS} = 10V, I _D = 7.0A		
Static Dialif-Source Off-Resistance (Note 6)	R _{DS (ON)}			0.036		V _{GS} = 4.5V, I _D = 6.0A		
Forward Transconductance (Notes 8 & 9)	g fs	_	16.5	_	S	V _{DS} = 15V, I _D = 7.1A		
Diode Forward Voltage (Note 8)	V_{SD}	_	0.82	1.2	V	I _S = 1.7A, V _{GS} = 0V		
Reverse recovery time (Note 9)	t _{rr}		12	_	ns	1 2 2 4 4 4 4 4 4 4 4 4 4		
Reverse recovery charge (Note 9)	Q _{rr}	_	4.8	_	nC	I _S = 2.2A, di/dt= 100A/μs		
DYNAMIC CHARACTERISTICS (Note 9)								
Input Capacitance	C _{iss}	_	608	_	pF			
Output Capacitance	Coss	_	132	_	pF	V _{DS} = 15V, V _{GS} = 0V -f= 1MHz		
Reverse Transfer Capacitance	C _{rss}	_	71	_	pF	1- 1101112		
Total Gate Charge	Qg	_	6.3	_	nC	V_{DS} = 15V, V_{GS} = 4.5V I_{D} = 7A		
Total Gate Charge	Qg	_	12.9	_	nC			
Gate-Source Charge	Q _{gs}	_	2.5	_	nC	$V_{DS} = 15V, V_{GS} = 10V$		
Gate-Drain Charge	Q _{gd}	_	2.5		nC	-I _D = 7A		
Turn-On Delay Time (Note 10)	t _{D(on)}	_	2.9	_	ns			
Turn-On Rise Time (Note 10)	t _r	_	3.3	_	ns	V_{DD} = 15V, V_{GS} = 10V I_{D} = 1A, $R_{G} \approx 6.0\Omega$		
Turn-Off Delay Time (Note 10)	t _{D(off)}	_	16	_	ns			
Turn-Off Fall Time (Note 10)	t _f		8		ns	<u>] </u>		

Notes:

- 8. Measured under pulsed conditions. Pulse width $\leq 300 \mu s;$ duty cycle $\leq 2\%$
- For design aid only, not subject to production testing.
 Switching characteristics are independent of operating junction temperatures.

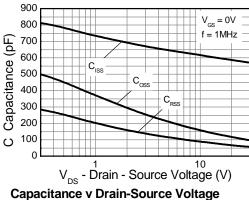


Typical Characteristics



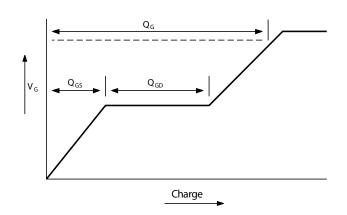


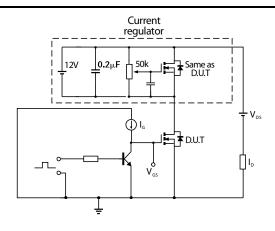
Typical Characteristics - continued



e Gate-Source Voltage v Gate Charge

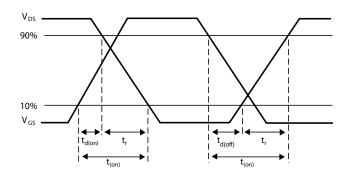
Test Circuits

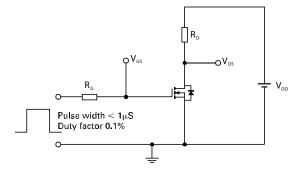




Basic gate charge waveform

Gate charge test circuit



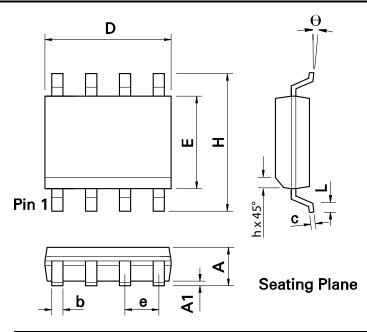


Switching time waveforms

Switching time test circuit

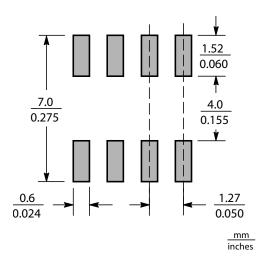


Package Outline Dimensions



DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	0.053	0.069	1.35	1.75	е	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
Н	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
Е	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Suggested Pad Layout







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